STRUCTURAL AND MICROWAVE DIELECTRIC PROPERTIES OF Sr_(1-X/2)Na_XNb₂O₆ FERROELECTRIC CERAMICS.

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Abstract

Strontium sodium niobate ceramics are prepared by solid state reaction method. The crystal structures of these ceramics are studied by X-ray powder diffraction method. These materials are found to crystallize in the tetragonal tungsten bronze type structure and the unit cell parameters are calculated. The microstructural features were studied using scanning electron microscope. The real and imaginary part of complex Permittivity of the sample is determined by cavity perturbation technique. It is observed that the real and imaginary part of complex Permittivity varies with frequency. The temperature coefficient of dielectric constant and resonant frequency is found to be very small.

Introduction

Progress in science and technology relies heavily on the development of new materials. Among these, "Smart" or "intelligent" materials have an important role to play in the development of new sophisticated devices. Smart materials and structures incorporate one or more of the following features: (a) Sensors or actuators which are either embedded within a structural material or bonded to the surface of that material. (b) Control capabilities which permit the behaviour of the material to respond to an external stimulus according to prescribed functional relationship or control algorithm. At a more sophisticated level, such smart materials become intelligent when they have the ability to respond intelligently and autonomously to dynamically changing environmental conditions. Potential applications of these are wide spread and have excited interest in industrial, military, commercial, medical, automotive and aerospace fields.

Resonators made of dielectric materials are used in a number of applications in frequency bands covering audio, RF, microwave and optical frequencies. They are basic elements in filters, oscillators; antennas etc. Microwave dielectric resonators are widely used in mobile telephones, satellite broadcasting systems, wave guides, capacitors, and frequency filters. Oxide ceramics are crucial elements in these microwave devices and a thorough understanding of the crystal structure and physical properties is essential for future development.

Dielectric materials with high dielectric constant ϵ_r , high Q, and small temperature coefficient of resonant frequency τ_f are particularly required for developing microwave dielectric resonator[1]. The experimental characterization of dielectric materials suitable for resonant cavities has been studied. [2, 3]. To analyse the temperature stability one must know the properties of all the materials used in the construction of the cavity device. Dielectric resonators exhibiting high Q factor and very low temperature coefficient of resonant frequency have been [4, 5], they promise to shrink the size and cost of waveguide cavities. Developing a zero τ_f material is probably the most difficult aspect of research in microwave dielectrics. The challenge now a days is to find ways to tune τ_f without reducing ϵ_r and maintaining quality factor (Q) [6]. When a particularly high Q is required, tantalates are used. The two main compounds in the market are Ba(Mg_{1/3}Ta_{2/3})O₃ (BMT) and Ba(Zn_{1/3}Ta_{2/3})O₃ (BZT). Although tantalates satisfy the high Q end of the market in terms of performance, Ta₂O₃ is expensive. Ideally, cheaper materials with equivalent Q/ ϵ_r , values based on either niobates or titanates must be found. Structural and dielectric properties of Sr_{1-x}Ba_xNb₂O₆ [7], Sr_{1-2x}K_xNb₂O₆ [8] and Ba₄Na₂Nb₂O₆ [9] ceramic materials had been investigated by various researchers. But, physical and microwave properties of Sr_{1-2x}K_xNb₂O₆ (SNN) is rarely seen in literature, and is hence taken up in the present study.

Experimental Procedure

Raw materials of high purity $SrCO_3$, Na_2CO_3 , Nb_2O_5 are weighed in accordance with chemical composition of $(Sr_{0.80}Na_{0.40}Nb_2O_6)$. The starting raw materials were mixed in a mortar with a pestle for 1 hour, dried and calcined at 1000 0 C for 4 hours. The powder was milled again with organic binder polyvinyl alcohol (PVA). It was pressed in to disc type and ring type specimens in suitable die of specific dimensions under pressure. It is then sintered at 1270 0 C for 4 hours in

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Form Approved OMB No. 0704-0188 air. The sintered samples were ground and polished before microwave measurements. X-ray diffraction patterns are taken to study the polycrystalline structure of the ceramic compositions. Analysis of the microstructural features of the composition is done using Scanning electron microscopy (SEM) photographs.

The resonant frequency and Q-factor were measured in the S-band using cavity perturbation method. The measurements were performed by inserting a small pellet sample into a rectangular cavity excited in the TE mode. The properties of the compositions were determined from the resultant change in the frequency and Q-factor. For the measurement of temperature coefficient of resonant frequency Courtney [10] method was used. The temperature coefficient of resonant frequency f₀ was measured in the range of 27 to 100 0 C. A dielectric resonator of (DR) with the diameter d = 16mm and length l = 6 mm was used for experiment. According to this method, different modes generated were classified and then ϵ_{r} was accurately calculated from TE_{onl} mode. The quality factor Q is determined from the 3 dB bandwidth of TE₀₁₁ mode.

Results and Discussion.

Figure 1 shows the X-ray diffraction pattern of $Sr_{1-2x}Na_xNb_2O_6$ ceramics sintered at 1270^0C . $Sr_{0.75}K_{0.5}Nb_2O_6$ composition has well defined peaks which are similar to tetragonal tungsten bronze type structure(TTB). The reflections were indexed on the basis of tetragonal symmetry. The calculation of lattice parameters from the d-values gives $a = 12.403 A^0$, $c = 3.922 A^0$. The axial ratio of $\sqrt{10} c/a$ is close to unity, which is characteristic of tetragonal tungsten bronze structure.

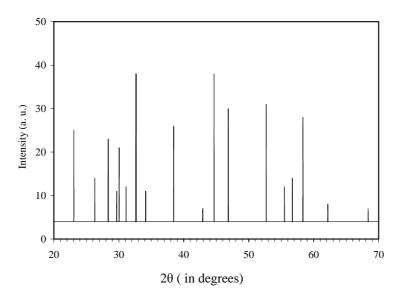


Figure 1. X-ray powder diffraction pattern of Sr_{0.8}Na_{0.4}Nb₂O₆ ceramics.

 $Sr_{0.80}Na_{0.40}Nb_2O_6$ is a polycrystalline ferroelectric ceramic having microstructure which can be observed by scanning electron microscopy. These microstructures consist of two inter penetrating, phases, the solid and the pore networks. The pores in the ceramic are connected to each other and the pore size distribution is comparably high. The characteristic pore structure and spacing depends on the method of preparation and can range between $2\mu m - 5 \mu m$. The dimensions of the grains and porous spaces can be calculated from scanning electron micrographs of $Sr_{0.80}Na_{0.40}Nb_2O_6$ sample shown in figure 2. These porous spaces are of much advantage, when we deal with sensing applications. These materials can absorb moisture or water into the porous spaces and are potential materials for microwave sensors and other related applications [8].

The dielectric parameters ϵ_r^{\prime} and $\epsilon_r^{\prime\prime}$ of the ceramic materials are obtained from the measured resonance frequencies f_o , f_s and the quality factors Q_o and Q_s for the TE_{10p} resonant mode. The complex permittivity (ϵ' and ϵ'') of the sample can then be calculated from these parameters using microwave cavity perturbation theory [11].

$$\varepsilon_r - 1 = \frac{f_o - f_s}{2f_s} \left(\frac{V_c}{V_s} \right) \tag{1}$$

$$\varepsilon_r^{"} = \frac{V_c}{4V_s} \left(\frac{Q_o - Q_s}{Q_o Q_s} \right) \tag{2}$$

where f_o is the resonant frequency of the air filled cavity (empty) f_s is the resonant frequency with the sample loaded in the cavity , V_c and V_s are the volume of cavity and sample respectively. Q_o and Q_s are the quality factors of the empty cavity and that of the sample loaded cavity. Figure 3 shows the real part of permittivity of SNN sample calculated using cavity perturbation theory, in the S-band frequency region. The real part of Permittivity is found to vary with frequency. Figure 4 shows the variation of imaginary part of permittivity with frequency.

For the measurement of temperature coefficient of resonant frequency, the cavity was placed in a hot chamber in which the temperature was stabilized. The resonant frequency and line width of the TE_{011} resonance measured when the mode become stationary at each value of temperature. T_f was calculated using the following equation [2].

$$T_f = \frac{1}{f_o} \frac{\Delta f_o}{\Delta T} \Big|_{T=T_o} \tag{1}$$

The dependence of the relative dielectric constant ε_r with temperature is specified by the coefficient T_{ε} , which can be calculated using the equation (2).

$$T_{\varepsilon} = \frac{1}{\varepsilon_r} \frac{\Delta \varepsilon_r}{\Delta T} \Big|_{T=T_o}$$
(2)

Where f_o is the resonant frequency at a given temperature and $\Delta f = f_0(T) - f_0$ (27 0 C). The temperature coefficient of resonant frequency, τ_f is the parameter which indicates the thermal stability of the resonator. The T_f was found to be very small, equal to 1.46137 ppm 0 C at 9.37GHz. Figure 5 shows the temperature variation of dielectric constant measured using Courtney method. The variation in dielectric constant is found to be negligibly small when temperature increases from 27^{0} C to 100^{0} C. The dielectric constant comes out to be a linear function of temperature as shown is figure 5. For the reference temperature 60^{0} C, the temperature coefficient of the dielectric constant is computed in accordance with equation (2)

$$T_{\epsilon} = (10.447 - 10.449) / [30.448 \times (100 - 27)] = -2.622 \text{ ppm/}^{0}\text{C}$$

Due to the linear behaviour, the same coefficient is valid over the entire range of temperature.

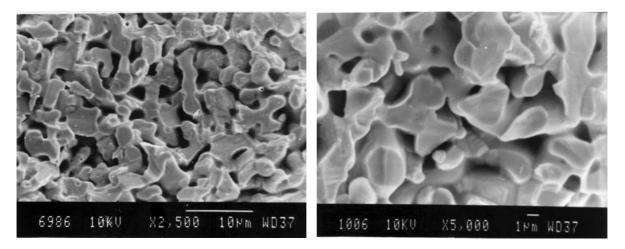
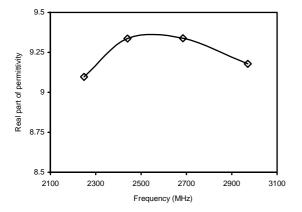


Figure 2 Scanning electron microscope photographs of SNN ceramics.

The variation of the resonant frequency with temperature is described in terms of physical parameters, one part is caused by the physical expansion of material parts, and the other by the change in the relative dielectric constant. The dielectric constant and temperature coefficient of resonant frequency depend mainly on the composition of the material. But loss factor varies from sample to sample of the same composition, indicating that the loss factor is sensitive to slight differences in crystallographic structure and microstructure of the material. One of the loss mechanisms in dielectric materials is the

resonance of electric dipoles in the molecule of the material. At a particular frequency, the dipole motion becomes resonant and will absorb power from the exciting electromagnetic field and the permittivity of the material is reduced.

Figure 6 shows the conductivity (S/m) variation of strontium barium niobate compositions with frequency. Conductivity is found to be varying with frequency in the S-band spectral region. The reflection characteristics of a DR made of SNN and fed from a coaxial feed are obtained. The dielectric resonator is having a bandwidth of 675 MHz at the resonant frequency 1855 MHz. The material exhibits good characteristics suitable for use as dielectric resonators and DR antennas.



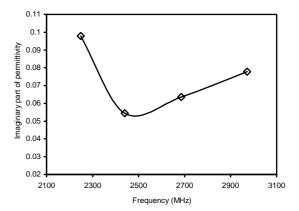
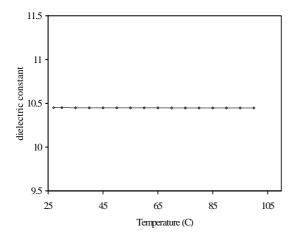
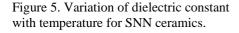


Figure 3. Frequency versus real part of complex Permittivity of SNN ceramics.

Figure 4. Frequency versus imaginary part of complex Permittivity of SN ceramics.





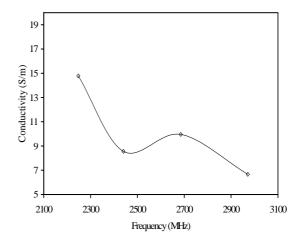


Figure 6. Frequency versus conductivity (S/m) of SNN ceramics.

Conclusion

Strontium sodium niobate, $Sr_{0.80}Na_{0.40}Nb_2O_6$, prepared by solid state reaction method showed tetragonal tungsten bronze type structure. The microstructural study shows the porous polycrystalline features of this composition. The microwave complex permittivity and conductivity are studied as a function of frequency. The temperature coefficient of dielectric

constant and resonant frequency is found to be very small. The material exhibits good characteristics suitable for use as dielectric resonators and DR antennas.

References

- [1] Y. C. Heiao, L. Wu, and C.C. Wei, "Microwave dielectric properties of (Zr Zn)TiO₄ ceramics", Mat.Res. Bull. vol. **23**, pp. 1687-1692, 1998.
- [2] Darko Kajfez, Siva Chebolu, Ahmed A. Kishk, Mohammed R. Abdul-Gaffoor, "Temperature dependence of composite microwave cavities." IEEE Trans. Microwave Theory and Tech., vol. MTT **49**, No.1, pp.80-85 January 2001.
- [3] A. P. Mourachkine and A. R. F. Barel, "Temperature dependence of the principal properties of dielectric resonators," Microwave J., Vol. **38**, pp. 220-233, Apr. 1995.
- [4] J. K. Plurde et al., "BaTi₉O₂₀ as a microwave dielectric resonator", J. Amer. Ceram. Soc., vol. 58, pp.418-420, Nov. 1975.
- [5] Toru Higashi and Toshihiko Makino, "Resonant frequency stability of the dielectric resonator on a dielectric substrate", IEEE Trans. Microwave Theory and Tech., Vol. MTT **29**, No.10, October 1981.
- [6] I. M. Reaney and R. Ubic, "Talking microwaves: A review of ceramics at the heart of the telecommunications network". International ceramics. Issue 1, pp. 48-52, 2000.
- [7] Nobuko S. VanDamme, Audrey E. Sutherland, Lori Jones, Keith Bridger and Stephen R. Winzer, "Fabrication of optically transparent and electrooptic strontium barium niobate ceramics". J. Am. Ceram. Soc., **74**(8), pp. 1785-92 1991.
- [8] Jaimon Yohannan, Joe Jacob, Anil Lonappan and K. T. Mathew "Effect of moisture content on dielectric properties of $Sr_{(1-x/2)}Na_xNb_2O_6$ ceramics at microwave frequencies." The 4th International Symposium on Humidity and Moisture, 16-19, Taipei, Taiwan, September 2002.
- [9] Jaimon Yohannan, K. Nanda kumar, Ravi Kumar, "Effect of heavy ion irradiation on the dielectric properties of selected barium sodium niobate ceramics", Nuclear Instruments and Methods in Physics Research B, **156**, pp. 227-230, 1999.
- [10] W. E. Courtney, "Analysis and evaluation method of measuring the complex Permittivity and permeability of microwave insulators," IEEE Trans. Microwave Theory and Tech., vol. MTT **18**, pp. 476-485, August 1970.
- [11] K.T.Mathew and U.Raveendranath, Cavity perturbation techniques for measuring dielectric parameters of water and other allied liquids, H.Baltes, W.Gopel and J.Hesse, (Eds.) Sensors Update, vol. 7, Wiley-VCH, Weinheim, Germany 2000.